

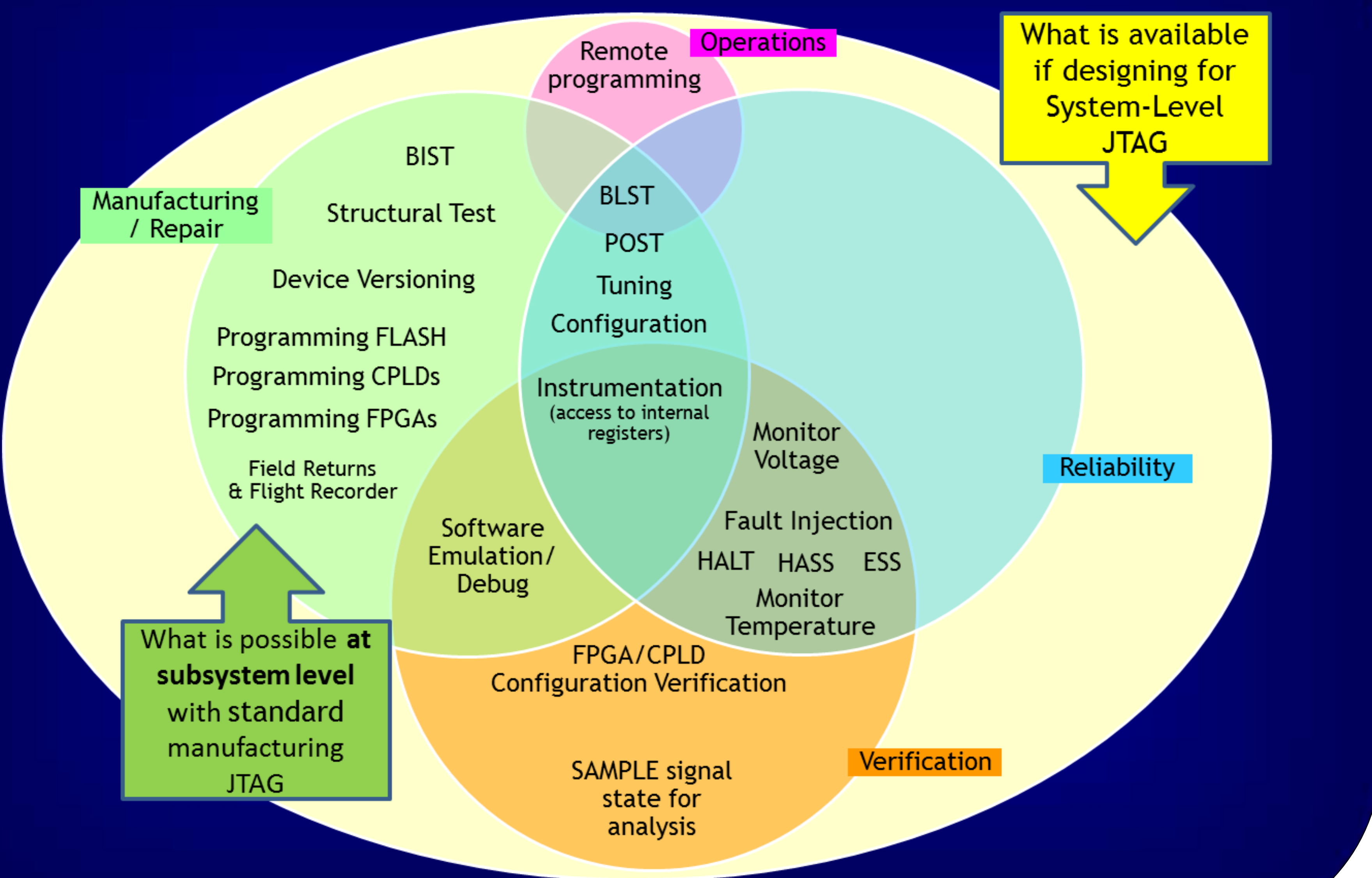
System Test Access Management (IEEE P2654 / STAM)

P2654

www.sjtag.org



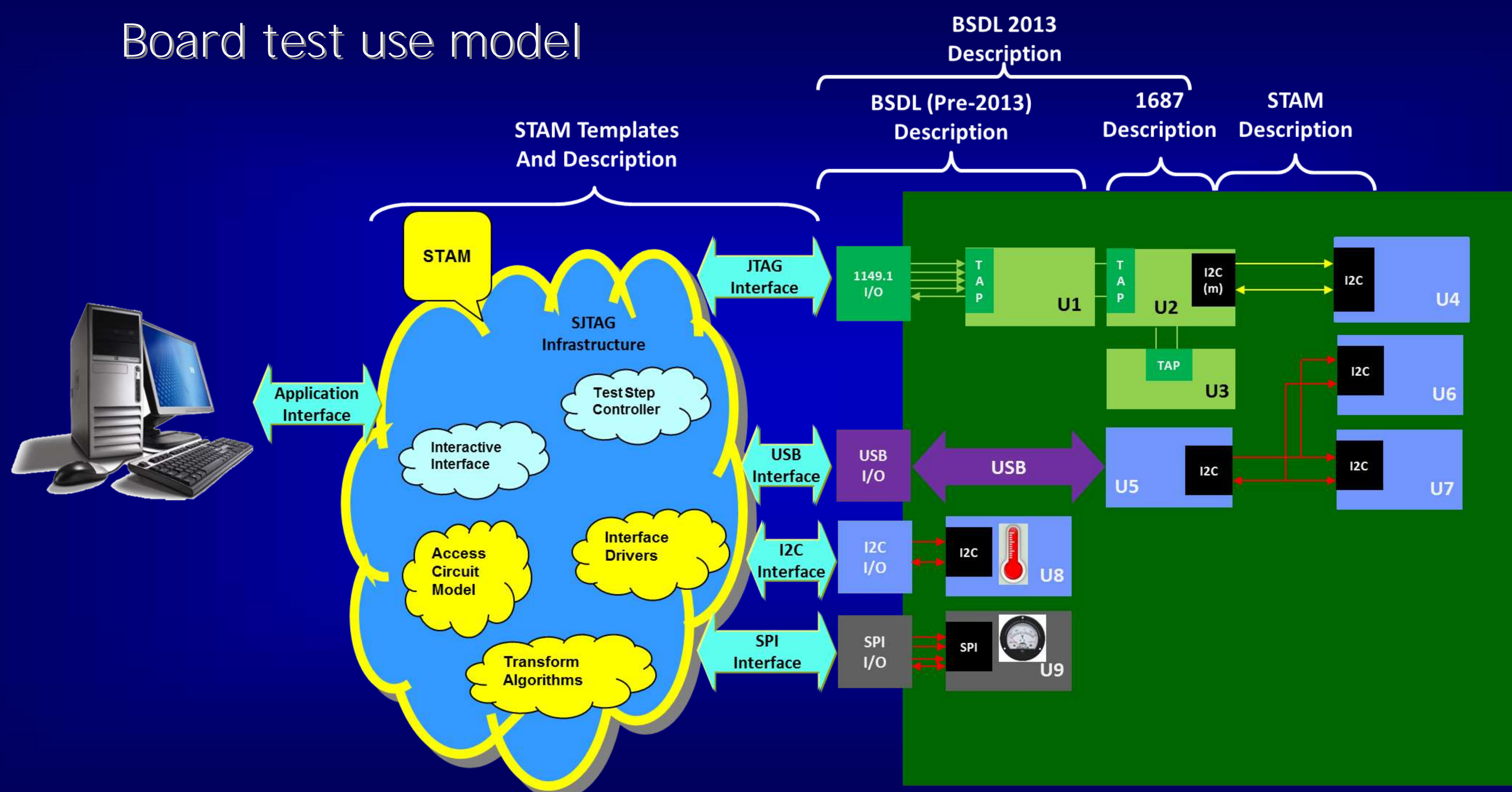
SJTAG Universe: Use cases in many domains



Concerns to Address

- ❖ Access to target (system topology)
- ❖ Test re-use through system hierarchy
- ❖ Hand-off to other standards
- ❖ Diagnostics support
- ❖ Data collection
- ❖ Data Analysis
- ❖ Black-box vs White-box test
- ❖ Security considerations

Board test use model



SJTAG/STAM Timeline

2005
 • Creation of the System-level JTAG Initiative (SJTAG)
 • Release of initial SJTAG White Paper

2009
 • Survey of user and industry experts

2018-Q2
 • Submission of PAR

2006
 • Survey of SJTAG Members

2017
 • Creation of System Test Access Management study group

2018-Q4
 • Formed IEEE TTSC sponsored Standard Working Group

2022 (Planned)
 • Initial version of a Standard for System Test Access Management

Regular meetings to identify problems, needs, requirements, analyze existing standards, etc.

Develop one or more Standards documents

Participating Organisations:

Ampere Computing ❖ Arm ❖ ASSET InterTech ❖ A. T. E. Solutions ❖ Cisco Systems ❖ Curtiss-Wright ❖ Dell ❖ DFT Solutions ❖ Firecron Ltd. ❖ GOEPEL Electronics ❖ Intel Corporation ❖ INTELLITECH Inc. ❖ JTAG Technologies ❖ Leonardo ❖ Lund University ❖ Marvell Inc. ❖ National Instruments ❖ Nvidia ❖ NXP Semiconductors ❖ Schweitzer Engineering Laboratories, Inc.